

Application/Control No.	T

Applicant(s)/Patent under Reexamination
HIBINO ET AL.

10/705,863 Examiner

Art Unit

Duc M. Nguyen

2685

	SEARCHED				
Class	Subclass	Date	Examiner		
455	193.1 193.2 193.3				
	199.1				
	179.1				
	180.2	-			
	188.1				
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	191.2 ·				
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	269 275				
	285->291				
	339 340				
333	124 129				
	132 32 172		/		
	174 227 231	3/6/08	PM		

INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
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(INCLUDING	SEARCH STRATEGY	<u>()</u>
	DATE	EXMR
EAST	2/21/2006	DN
EAST	3/6/2006	DN